TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIV)

2SK3566

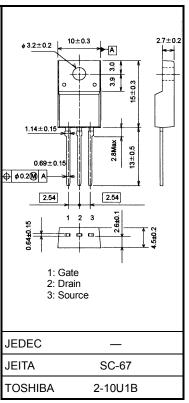
Switching Regulator Applications

Unit: mm

- Low drain-source ON resistance: RDS (ON) = 5.6Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 2.0 \text{ S (typ.)}$
- Low leakage current: IDSS = 100 μ A (VDS = 720 V)
- Enhancement-mode: $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	900	V	
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	900	V	
Gate-source voltage		V_{GSS}	±30	V	
	DC (Note 1)	I _D	2.5	А	
Drain current	Pulse (t = 1 ms) (Note 1)	I _{DP}	7.5		
Drain power dissipati	on (Tc = 25°C)	PD	40	W	
Single pulse avalanche energy (Note 2)		E _{AS}	216	mJ	
Avalanche current		I _{AR}	2.5	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	4	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

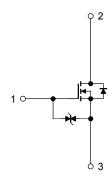


Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit	
Thermal resistance, channel to case	R _{th (ch-c)}	3.125	°C/W	
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W	



- Note 1: Please use devices on conditions that the channel temperature is below 150°C.
- Note 2: V_{DD} = 90 V, T_{ch} = 25°C, L = 63.4 mH, I_{AR} = 2.5 A, R_G = 25 Ω
- Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.



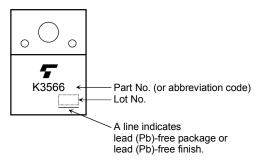
Electrical Characteristics (Ta = 25°C)

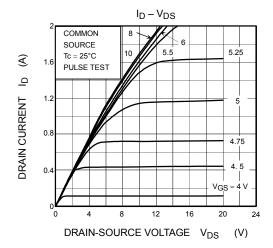
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Gate-source brea	ıkdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{GS} = 0 \ V$	±30	_	_	V
Drain cut-off curre	ent	I _{DSS}	V _{DS} = 720 V, V _{GS} = 0 V		_	100	μΑ
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	900	_	_	V
Gate threshold vo	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 1.5 A		5.6	6.4	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 20 V, I _D = 1.5 A	1.0	2.0	_	S
Input capacitance		C _{iss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz		470	_	pF
Reverse transfer capacitance		C _{rss}		_	10	_	
Output capacitance		Coss			50	_	
Switching time	Rise time	t _r	V_{GS} $V_{D} = 1.5 \text{ A}$ V_{OUT} V_{GS} $V_{DD} \approx 200 \text{ V}$	_	20	_	
	Turn-on time	t _{on}		_	60	_	
	Fall time	t _f		_	30	_	ns
	Turn-off time	t _{off}	Duty \leq 1%, $t_W = 10 \mu s$	_	100	_	
Total gate charge		Qg		_	12	_	
Gate-source charge		Qgs	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$	_	7	_	nC
Gate-drain charge		Q _{gd}		_	5		

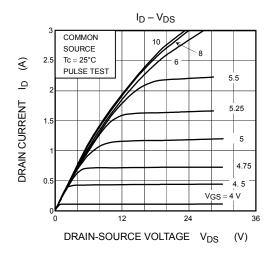
Source-Drain Ratings and Characteristics (Ta = 25°C)

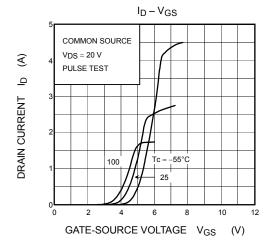
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	2.5	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	7.5	Α
Forward voltage (diode)	V _{DSF}	$I_{DR} = 2.5 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 2.5 \text{ A}, V_{GS} = 0 \text{ V},$	_	720	_	ns
Reverse recovery charge	Q _{rr}	dI _{DR} /dt = 100 A/μs	_	3.6	_	μС

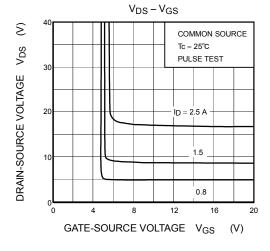
Marking

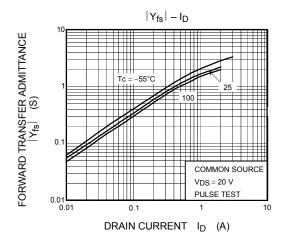


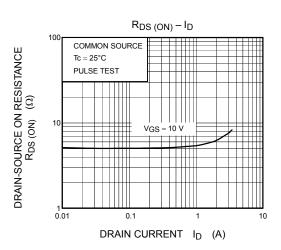


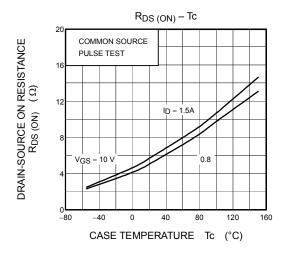


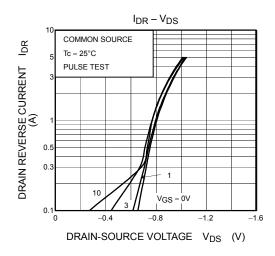


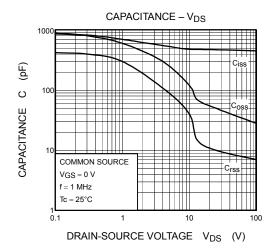


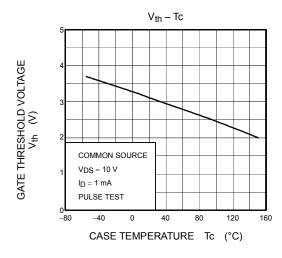


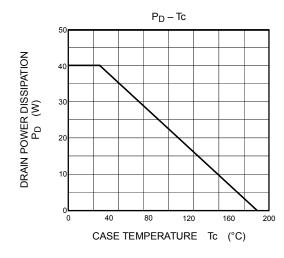


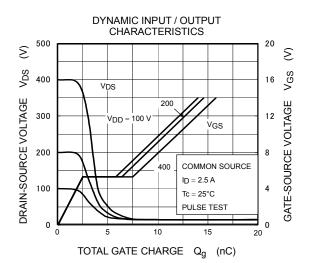




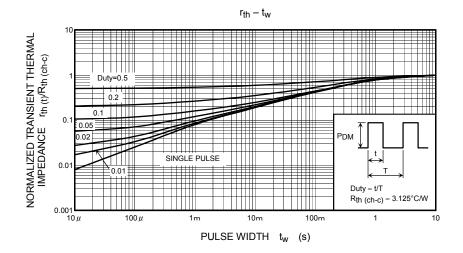


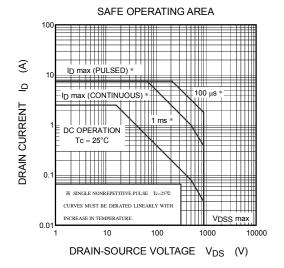


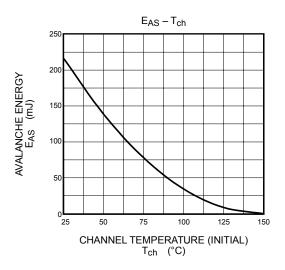


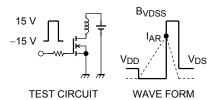


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$$R_G = 25 \Omega$$

$$V_{DD} = 90 \text{ V, } L = 43.4 \text{mH}$$

$$E_{AS} = \frac{1}{2} \cdot L \cdot l^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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